

PROBE CARD

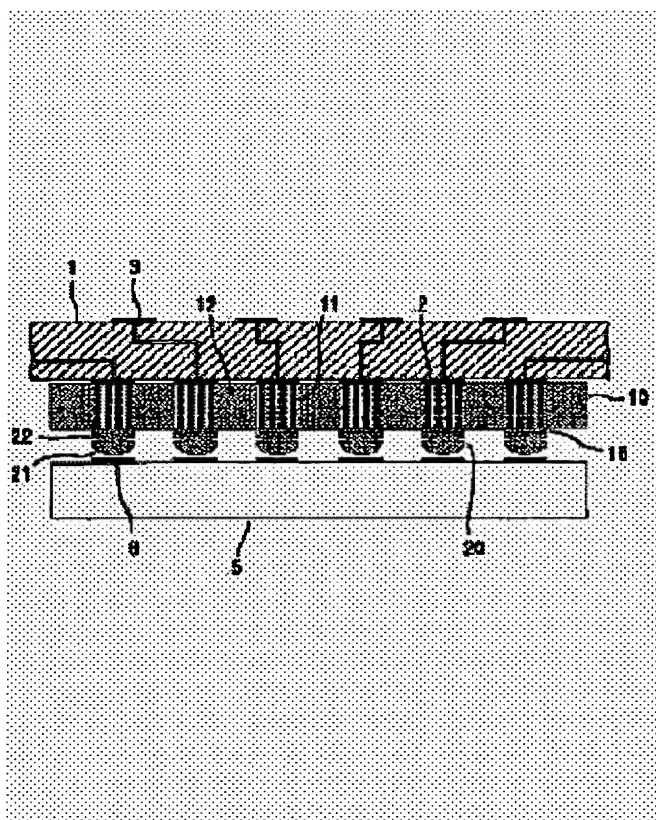
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Abstract of JP2001050983

PROBLEM TO BE SOLVED: To surely effect electrical connection, even in case of an electrode under test having an oxide film on the surface by integrally providing respective conductive parts of an anisotropic conductive sheet with a protrusion electrode.

SOLUTION: A circuit board 1 under test is placed, such that the connection electrode 2 thereof is positioned on the conductive part 11 of an anisotropic conductive sheet 10 in a probe card. A wafer 5 is placed under the probe card, such that the electrode 6 under test thereof faces a protrusion electrode 20. When the circuit board 1 is moved to approach the wafer 5, the protrusion electrode 20 presses the electrode 6 under test and breaks through an oxide coating on the surface. The conductive sheet 10 is deformed to compress in the thickness direction, and a conductive path is formed in that direction at the conductive part 11. Consequently, the connection electrode 2 is connected electrically with the electrode 6 under test and the circuit board 1, the probe card and the wafer 5 are secured under that state before a required test is carried out.



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